

Circuit Reliability: Major Roadblock in Future Technology?

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Abstract

As technology scales, circuit reliability has become a major issue. This panel focuses on circuit reliability in current and future technology. Topics for discussion include the following:

1. Major reliability issues in advanced CMOS. Which is the most critical?
2. Major reliability issues in beyond CMOS technology. Any difference?
3. Major reliability issues at 3D IC, automotive, and medical electronics. Reliable hardware platform for automotive applications.
4. The role of EDA in improving circuit reliability.